

REMARKS

The application has been carefully reviewed in light of the Office Action dated August 19, 2004. Applicant gratefully acknowledges the Examiner's statement that claims 6-11, 20, 21, 29, 30, 43, 44, 46, 47 and 52 contain allowable subject matter. Non-elected claims 53, 55-76 and 78-98 have been canceled. The title of the invention has been amended to more closely reflect the subject matter of the claimed inventions. Claims 1, 3-33, 35-47 and 49-52 remain pending in this case.

Claims 1, 3-5, 12-14, 17-19 and 51 stand rejected under 35 U.S.C. § 102(b) as being anticipated by Yasui et al. (U.S. Patent No. 4,278,971). Applicant respectfully traverses the rejection and requests reconsideration.

Claim 1 recites a method for measuring a parameter of a circuit under test, the method comprising "disconnecting [a] test circuit from respective voltage terminals providing . . . first and second voltage levels; and measuring said parameter of said circuit under test with said test circuit." [Emphasis added.] Yasui does not teach or suggest these limitations of claim 1.

To the contrary, Yasui discloses measuring the parameter of the circuit under test (i.e., whether the charged voltage of condenser 6 is maintained lower than the reference voltage, and whether the reference voltage is maintained lower than the divided constant voltage during the period of time t1, as indicated by indication lamp 18) only when the test circuit is connected to a power source (i.e., when ignition switch 1a is closed). Yasui at column 4, lines 1-2 and lines 15-26.

Nowhere does Yasui teach or suggest disconnecting the test circuit from respective voltage terminals and then measuring the parameter under test with the test circuit. In fact, claim 1 of Yasui discloses "a storage condenser connected to said power

source” and “second storage means connected to said power source.” [Emphasis added.] At least for these reasons, claim 1 is allowable over Yasui.

Claim 51 recites a semiconductor die comprising a first storage capacitor “for providing power to [a] comparator when said comparator is disconnected from [a] power source.”

Yasui, to the contrary, discloses that when one of conductors 1b, 1c is disconnected during a vehicle collision, the storage condenser 6 is discharged through the diode 7 to energize the primer 2. Yasui at column 2, lines 40-44. The primer 2 is not a comparator, as recited in claim 51. At least for these reasons, claim 51 is allowable over Yasui.

Claims 3-5, 12-14 and 17-19 depend from claim 1 and are also allowable over Yasui at least for the same reasons mentioned above in connection with claim 1 and also because Yasui fails to teach or suggest the respective inventive combinations defined by claims 3-5, 12-14 and 17-19.

Claims 22 and 23 stand rejected under 35 U.S.C. § 103(a) as being unpatentable over Yasui in view of De Jong et al. (U.S. Patent No. 6,664,798). Applicant respectfully traverses the rejection and requests reconsideration.

Claims 22 and 23 depend from claim 1 and while De Jong does appear to disclose the problems associated with ground bounce and power droop, De Jong does not cure the defects of Yasui as outlined above. MPEP § 2143 requires that the prior art references, when combined, must teach or suggest all of the claim limitations. The requirements of § 2143 are not met with Yasui and De Jong. Accordingly, at least for the same reasons mentioned above in connection with claim 1, claims 22 and 23 are allowable over the combination of Yasui and De Jong.

Claims 15, 16, 24-28, 31, 32, 35-41, 45 and 49 stand rejected under 35 U.S.C. § 103(a) as being unpatentable over Yasui in view of Frech et al. (U.S. Patent Publication No. 2002/0125897). Applicant respectfully traverses the rejection and requests reconsideration.

Claims 15 and 16 depend from claim 1 and while Frech appears to disclose the use of a switch to disconnect a power source from a circuit, Frech does not cure the defects of Yasui as mentioned above in connection with claim 1. At least for those reasons, claims 15 and 16 are allowable over the combination of Yasui and Frech.

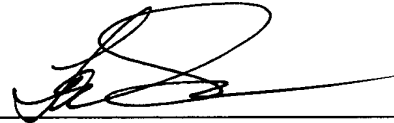
Claims 24 and 38 recite a test circuit for measuring a parameter of a circuit under test, comprising a measuring portion for measuring a parameter of said circuit under test “while said . . . test circuit is disconnected from [voltage] terminals.” At least for the same reasons mentioned above in connection with claim 1, claims 24 and 38 are allowable over the combination of Yasui and Frech.

Claims 25-28, 31, 32, 35-37, 39-41, 45 and 49 depend from claims 24 and 38 and are allowable at least for the reasons mentioned above and also because none of the cited references, taken alone or in combination, teaches or suggests the respective inventive combinations defined by claims 25-28, 31, 32, 35-37, 39-41, 45 and 49.

In view of the above, each of the presently pending claims in this application is believed to be in immediate condition for allowance. Accordingly, the Examiner is respectfully requested to withdraw the outstanding rejections and to pass this application to issue.

Dated: October 8, 2004

Respectfully submitted,

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